

Search Notes

Application/Control No.

10/517,269

Examiner

BIN SHEN

Applicant(s)/Patent under
Reexamination

JANG ET AL.

Art Unit

1657

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated search.	5/20/2008	BS